Metal thin film chip resistors
(the highest reliability and precision)

■URG series **AEC-Q200 Compliant**

Features

- The tightest resistance tolerance: +/-0.01%
- The smallest temperature coefficient of resistance: ±1ppm/°C
- Long term stability with inorganic passivation
- Thin film structure enabling low noise and anti-sulfur

Applications

- Industrial measurement, electrical scales
- High precision sensors, medical electronics

◆Part numbering system

URG 2012 L - 102 - L - T1

- URG: Series code
- 2012: Size: URG1608, URG2012, URG3216, URG5025, URG6432
- L: Temperature coefficient of resistance
- 102: Nominal resistance value (E-24: 3 digit, E-96: 4 digit, URG3216, URG5025, URG6432: all 4 digit)
- L: Resistance tolerance
- T1: Packaging quantity: T1(1,000pcs), T05(500pcs), T01(100pcs)

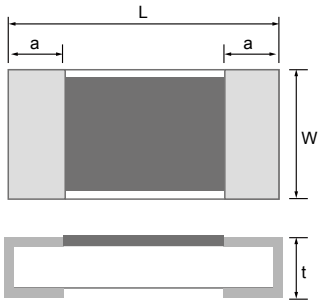
◆Electrical Specification

Type	Power ratings	Temperature coefficient of resistance *1 (ppm/°C)	Resistance range(Ω) Resistance tolerance ±0.01% (L)	±0.02% (P)	±0.05% (W)	±0.1% (B)	±0.5% (D)	Maximum voltage	Resistance value series	Operating temperature	Packaging quantity
URG1608	1/16W	±1(K)	100≦R≦7.5k					100V	E24, E96	-55℃ ~ 155℃	T1
		±2(L)									
URG2012	1/10W	±1(K)	100≦R≦36k					150V			T05
		±2(L)									
URG3216	1/4W	±1(K)	100≦R≦68k					200V			T01
		±2(L)									
URG5025	1/2W	±1(K)	100≦R≦150k					300V			T01
		±2(L)									
URG6432	3/4W	±1(K)	100≦R≦200k					300V			
		±2(L)									

*1 Applicable TCR range -20°C ~ 125°C

***Contact us for requirements not listed in above table.**

◆Dimensions



Type	Size (inch)	L	W	a	t
URG1608	0603	1.60±0.20	0.80+0.25/−0.20	0.30±0.20	0.40+0.15/−0.10
URG2012	0805	2.00±0.20	1.25+0.25/−0.20	0.40±0.20	0.40+0.15/−0.10
URG3216	1206	3.20±0.20	1.60±0.25	0.50±0.25	0.40+0.15/−0.10
URG5025	2010	5.00±0.20	2.50±0.25	0.60±0.25	0.45+0.15/-0.10
URG6432	2512	6.40+0.20/−0.40	3.20±0.25	0.75±0.25	0.45±0.20

(unit : mm)

◆Reliability specification

Test items	Condition (test methods (MIL-PRF-55342/JIS C5201-1)	Standard
Short time overload	2.5 x rated voltage,*1 5seconds	±0.02%+0.01Ω
Life (biased)	70°C, rated voltage,*1 90min on 30min off, 2000hours	±0.02%+0.01Ω(R≧250Ω)
		±0.05%+0.01Ω(R<250Ω)
High temperature high humidity	85°C, 85%RH, 1/10 of rated power, 90min on 30min off, 1000hours	±0.05%+0.01Ω
Temperature shock	-65°C (15min) ~ 150°C (15min) 100cycles	±0.02%+0.01Ω
High temperature exposure	155°C, no bias, 1000hours	±0.05%+0.01Ω
Resistance to soldering heat	235±5°C, 30 seconds (reflow), (by MIL-PRF-55342)	±0.01%+0.01Ω

*1 Rated voltage is given by $E=\sqrt{R \times P}$
E= rated voltage (V), R=nominal resistance value(Ω), P=rated power(W)
If rated voltage exceeds maximum voltage /element, maximum voltage/element is the rated voltage.

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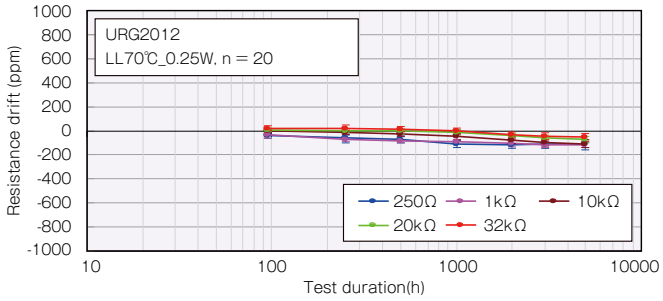
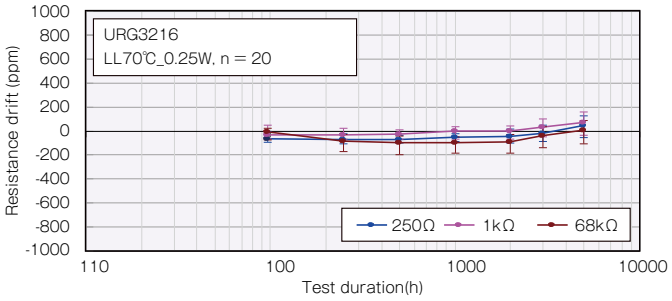
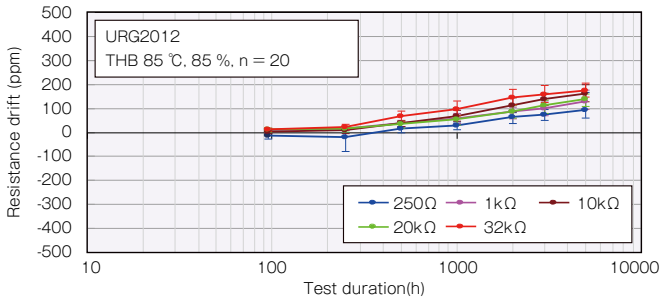
◆Reliability test data

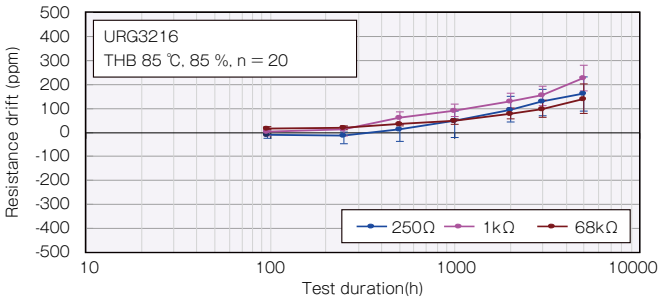
○Biased life test



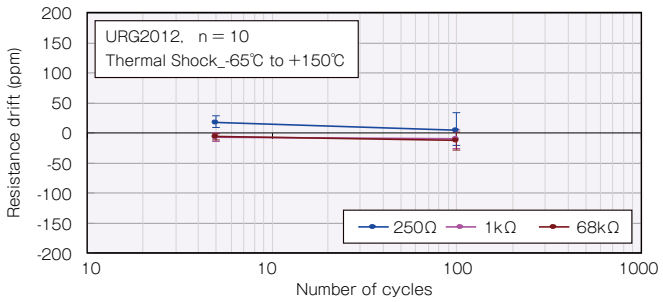


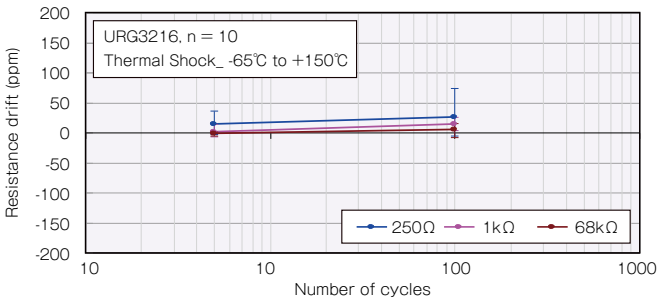
○High temperature high humidity (biased)



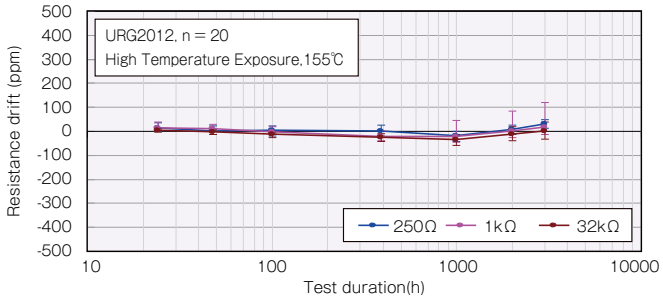


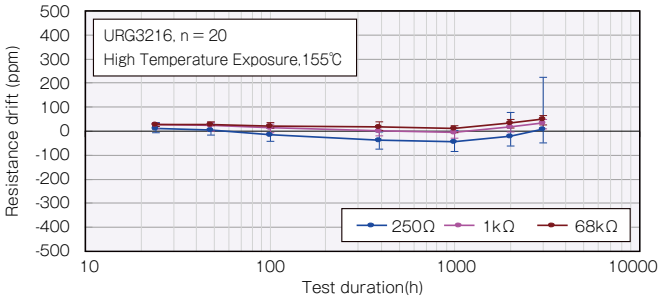
○Temperature shock





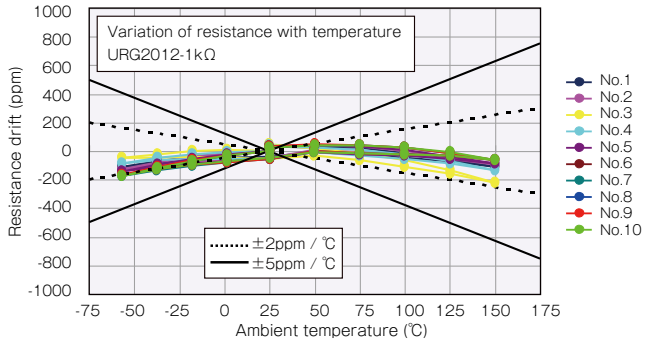
○High temperature exposure

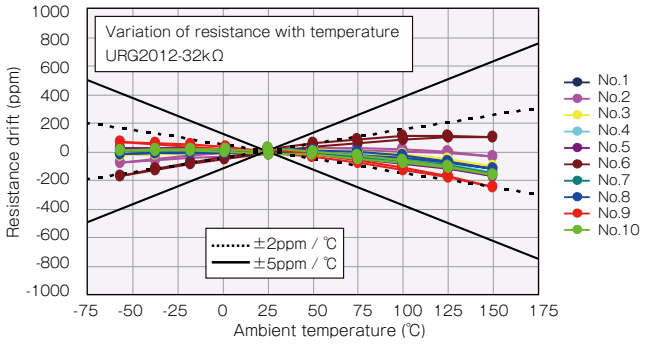




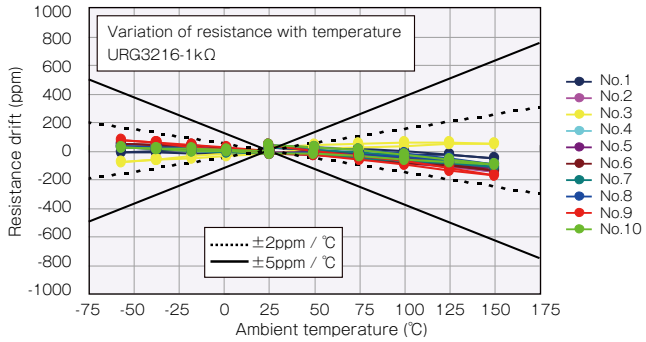
◆Temperature coefficient of Resistance

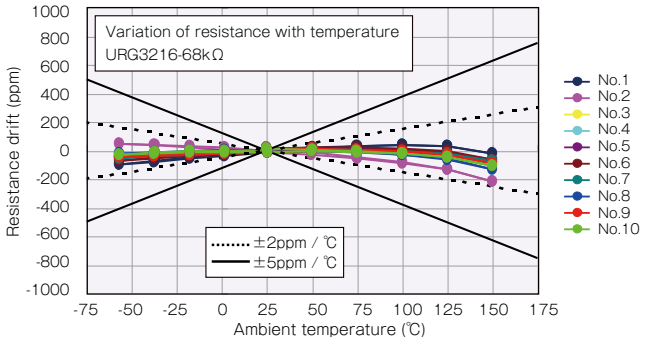
○URG2012





○URG3216





◆Derating Curve